

W7-X Dispersions Interferometer's Current Signal Processing and Future Bayesian Model Data Analysis.

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The dispersion interferometer (DI) diagnostic:

- Can be used to measure line integrated electron density.
- Performs data acquisition and processing with an FPGA.



Advantages over 2-Color Interferometer:

- Less sensible to vibrations of optical components.
- Reflection reduced and less sensible to base length changes.

$$V_p = I_1 + I_2 + 2\sqrt{I_1 I_2} \cos(2m * \sin(\omega t) + \varphi)$$

For Wendelstein 7-X (W7-X)

- A fast/real time variant of this analysis is desired.
- An acceleration of the modeling and the inversion through multi-core and/or FPGA system.





















Data Acquisition: SIS8900 digitizer with connection to SIS8300-L

Raw Data Storage: Currently handled through PCIe backplane communication.



Real-time Data Transmission: Connection to Real time network using 1000BASE-SX transceivers at 1ms time resolution.

DSP Control/ Configuration: Possible through PCIe access to register bank.





Hardware + Forward modeling + Bayesian Inference:

- Find hardware analogue of components in a model for a proper modeling.
- Standard optimizers as solvers.
- Solve the inversion problem for many complete forward models.



If implemented in real time the approach could be useful for diverse applications

- Generating signals for control loops.
- Local hardware determination of required parameters.
- Would considerably benefit multiple signal analyses of different systems.
- Can be improved by swapping model due to its modularity and standard solvers.





Possible challenges:

- Limitations in parallelism feasibility.
- Solvers or optimizer slowing processing.
- Inversion of highly non-linear models.

Solution approach and requirements:

- Hardware/Software solution combined with FPGA.
- Requires fast communication between FPGA/Software.
- GPU or multicore processing of inversion.





Vielen Dank für Ihre Aufmerksamkeit